

PXN6R7-30QLJ-VB Datasheet N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^a	Q _g (Typ.)			
30	0.0045 at V _{GS} = 10 V	40	26.5 nC			
30	0.0060 at V _{GS} = 4.5 V	33.3	20.5 110			

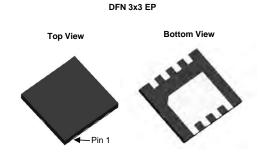
FEATURES

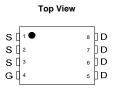
- · Halogen-free
- Trench Power MOSFET
- 100 % R_g and UIS Tested

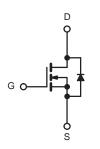


APPLICATIONS

- DC/DC Conversion
 - Low-Side Switch
- Notebook PC
- Gaming







N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V_{DS}	30	V		
Gate-Source Voltage		V_{GS}	± 20	v	
	T _C = 25 °C		40		
Continuous Drain Current (T _{.I} = 150 °C)	T _C = 70 °C	I _D	32.6		
Continuodo Brain Garretti (1 j = 100 °C)	T _A = 25 °C	טי	31.5 ^{b, c}		
	T _A = 70 °C	T _A = 70 °C	27.1 ^{b, c}	A	
Pulsed Drain Current		I _{DM}	70		
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	5.4		
	T _A = 25 °C	'S	2.7 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	40		
Avalanche Energy		E _{AS}	80	mJ	
	T _C = 25 °C		6.0		
Maximum Power Dissipation	T _C = 70 °C	P _D	3.3	W	
Maximum rower Dissipation	T _A = 25 °C	ן ט'י	3.0 ^{b, c}		
	T _A = 70 °C]	1.9 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R_{thJA}	33	42	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	16	21	C/ V V		

Notes:

- a. Based on $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. Maximum under Steady State conditions is 85 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	30			V	
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J			27		>//0	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	- I _D = 250 μA		- 5.6		mV/°	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.5		3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zara Oata Waltana Brain Oarrani	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V			1	μΑ	
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C		10			
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
		V _{GS} = 10 V, I _D = 15 A		0.0045		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 10 A		0.0060			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 15 A		75		S	
Dynamic ^b			L			l	
Input Capacitance	C _{iss}			2545		pF	
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		450			
Reverse Transfer Capacitance	C _{rss}	1		140			
Total Gate Charge		V _{DS} = 15 V, V _{GS} = 10 V, I _D = 10 A		62		nC	
				26.5			
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		8.5			
Gate-Drain Charge	Q _{gd}	1		7.3			
Gate Resistance	R _g	f = 1 MHz	0.2	1.1	2.2	Ω	
Turn-On Delay Time	t _{d(on)}			35	60		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		16	30		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		48	85		
Fall Time	t _f	1		16	30		
Turn-On Delay Time	t _{d(on)}			18	35	- ns -	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		8	16		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		41	75		
Fall Time	t _f			8	18		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			5.4		
Pulse Diode Forward Current ^a	I _{SM}				70	Α	
Body Diode Voltage	V _{SD}	I _S = 3 A		0.72	1.1	V	
Body Diode Reverse Recovery Time	t _{rr}			33	65	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I = 10 A dl/dt = 100 A/va T = 05 °C		27	54	nC	
Reverse Recovery Fall Time	ta	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		17			
Reverse Recovery Rise Time		t _b		16		ns	

Notes:

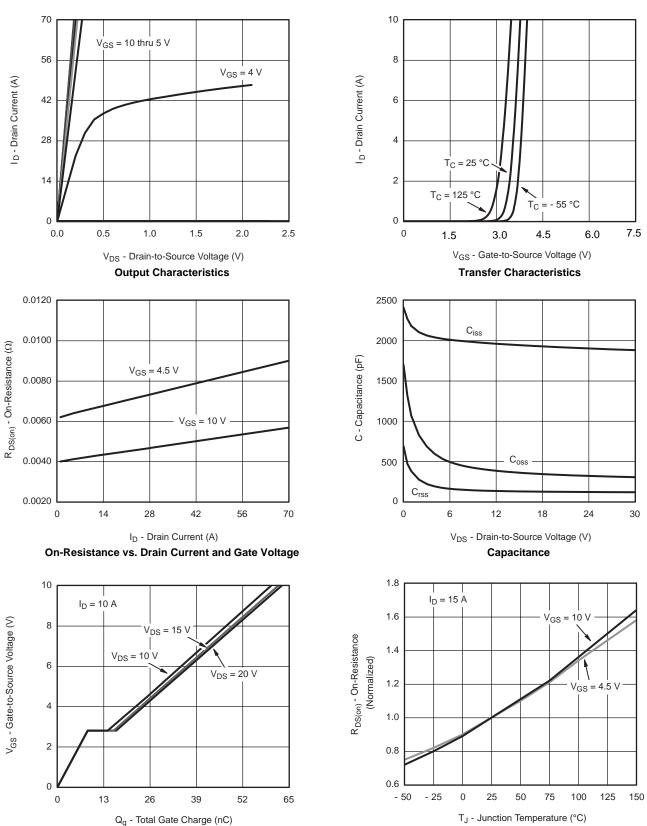
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$

b. Guaranteed by design, not subject to production testing.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



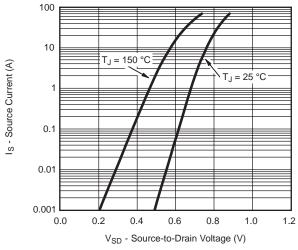
服务热线:400-655-8788

Gate Charge

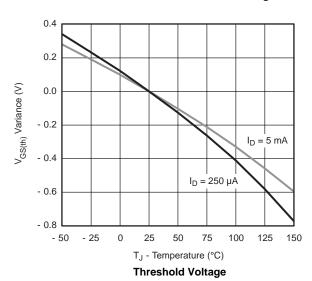
On-Resistance vs. Junction Temperature



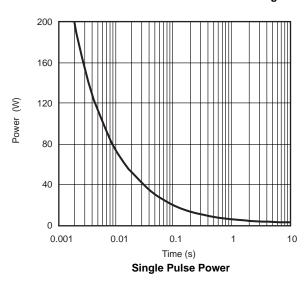
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

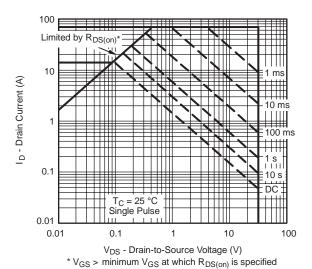


Source-Drain Diode Forward Voltage



0.025 $I_D = 15 \text{ A}$ 0.020 R_{DS(on)} - On-Resistance (Ω) 0.015 0.010 T_J = 125 °C 0.005 $T_J = 25^{\circ}C$ 0.000 1 2 3 4 5 0 6 8 10

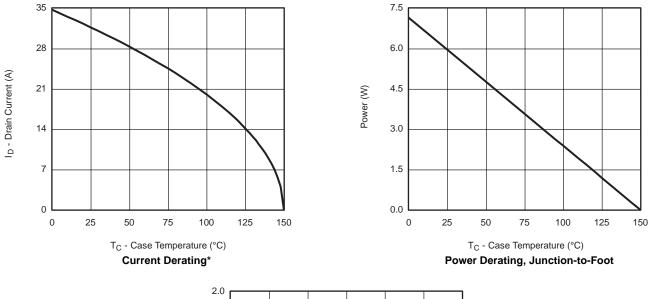


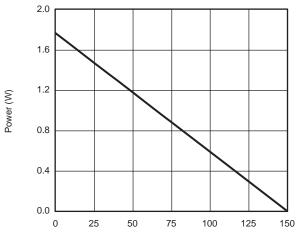


Safe Operating Area, Junction-to-Ambient



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



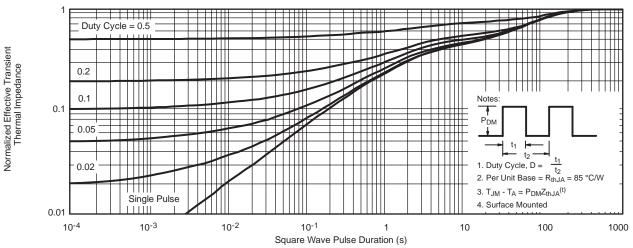


T_A - Ambient Temperature (°C) **Power, Junction-to-Ambient**

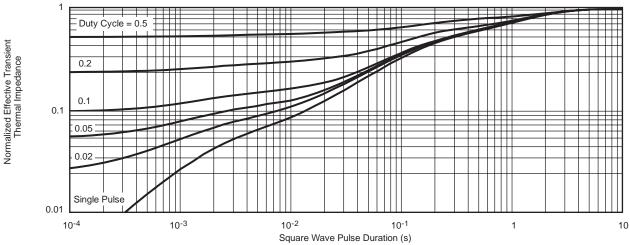
^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



TYPICAL CHARACTERISTICS 25 C, unless otherwise noted

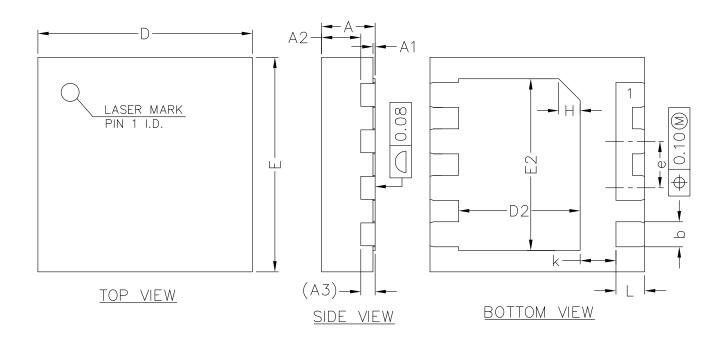


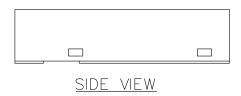
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot







COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX	
Α	0.70	0.75	0.80	
A1	0.00	0.02	0.05	
A2	0.50	0.55	0.60	
А3	0.20REF			
b	0.30	0.35	0.40	
D	2.90	3.00	3.10	
Е	2.90	3.00	3.10	
D2	1.60	1.70	1.80	
E2	2.30	2.40	2.50	
е	0.55	0.65	0.75	
K	0.40	0.50	0.60	
L	0.35	0.40	0.45	



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